# External Quantum Efficiency Measurement - ELQ Series

Capable of measuring the widest wavelength range (350-1700 nm), best-in-class SNR m/



### O Details

ELQ Series (External Quantum Efficiency Measurement System) is an industry-leading EQE measurement system with signal-to-noise ratio and/ow stray light characteristics to ensure measurement results.

### • Features





- EQE can be measured independently of the emission angle characteristics of the sample as the integrating sphere is integrated.
- Best-in-class signal-to-noise ratio (SNR) and quantum efficiency > Low-light detection using the most advanced sensing module and avoid spectral distortion
- The standard wavelength band is 350-780 nm, and the widest wavelength band among existing EQE measurement equipment can also be applied (350-1700nm)



- Easy-to-use software
- Compact: Easy to use and transport
- Automatic measurement after selecting wavelength and interval
- Efficient Operation: Once set-up is fixed, calibration is not required each time.



Outstanding performance at an affordable price

# **Applications**

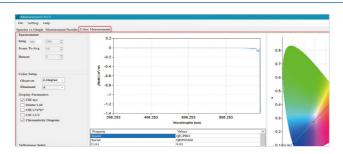
- ▶ Inorganic Electroluminescence
- ▶ Organic Electroluminescence
- ▶ Molecular thin film EL Devicce

## O Measurement Parameters

- ✓ External quantum efficiency(EQE)
- ✓ Total luminous flux (lumen)
- ✓ Spectral irradiance (W/m2/nm)
- ✓ Current density
- ✓ Luminance (cd/m²)
- ✓ Luminous Efficiency (CE, cd/A)
- ✓ Tristimulus value X, Y, Z

- ✓ Quantum Efficiency current density curve
- √ Chromatic Coordinates (x,y)
- ✓ Radiant Flux
- ✓ Brightness
- ✓ Main Wavelength
- ✓ Power Efficiency (SI, Im/W)
- ✓ Chromaticity coordinates (x, y)

# Software Window Example



### **Measurement Setup**

- ▶ Measurement Unit Setup
- ▶ Display Parameters
- ► Minimum current/voltage
- ▶ Maximum current/voltage
- ▶ etc

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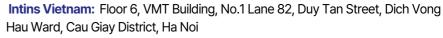
#### Measurement Results

- ▶ Current Density/EQE
- ▶ Current Density/Power Efficiency
- ▶ Current Density/Luminance
- ▶ Current Density/Luminance Efficiency

# O Specifications

Wavelength Range	Standard : 350 nm - 780 nm / Option : 350 nm - 1700 nm
Resolution	2 nm (FWHM)
Source Meter	Keithley2450 (Standard)
3.3" Size Integrating Sphere	
1000 um Optical Fiber	
ELQ Software	







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<sup>\*</sup> Software can be customized for customers. Please refer as a general example